







**CD54ACT74, CD74ACT74** 

SCHS321A - DECEMBER 2002 - REVISED JULY 2024

## CDx4ACT74 Dual Positive-Edge-Triggered D-type Flip-flops with Clear and Preset

#### 1 Features

- Inputs are TTL-voltage compatible
- Speed of bipolar F, AS, and S, with significantly reduced power consumption
- Balanced propagation delays
- ±24mA output drive current
  - Fanout to 15 F devices
- SCR-latchup-resistant CMOS process and circuit
- Exceeds 2kV ESD protection per MIL-STD-883, method 3015

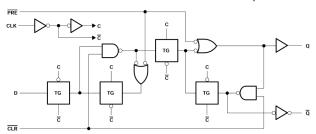
### 2 Description

The 'ACT74 dual positive-edge-triggered devices are D-type flip-flops.

#### **Device Information**

PART NUMBER	PACKAGE <sup>(1)</sup>	PACKAGE SIZE(2)	BODY SIZE(3)
	D (SOIC, 14)	8.65mm × 6mm	8.65mm × 3.9mm
CDx4ACT74	N (PDIP, 14)	19.3mm × 9.4mm	19.3mm × 6.35mm
	J (CDIP, 14)	19.56mm x 7.9mm	19.56mm × 6.67mm

- For more information, see Section 10. (1)
- The package size (length × width) is a nominal value and includes pins, where applicable.
- (3) The body size (length × width) is a nominal value and does not include pins.



Logic Diagram, Each Flip-flop (Positive Logic)



### **Table of Contents**

1 Features1	6.2 Functional Block Diagram	9
2 Description1	6.3 Device Functional Modes	9
3 Pin Configuration and Functions3	7 Application and Implementation	. 10
4 Specifications4	7.1 Power Supply Recommendations	.10
4.1 Absolute Maximum Ratings4	7.2 Layout	. 10
4.2 ESD Ratings	8 Device and Documentation Support	. 11
4.3 Recommended Operating Conditions4	8.1 Documentation Support (Analog)	11
4.4 Thermal Information4	8.2 Receiving Notification of Documentation Updates	. 11
4.5 Electrical Characteristics5	8.3 Support Resources	. 11
4.6 Timing Requirements5	8.4 Trademarks	. 11
4.7 Switching Characteristics5	8.5 Electrostatic Discharge Caution	. 11
4.8 Operating Characteristics	8.6 Glossary	. 11
5 Parameter Measurement Information7	9 Revision History	. 11
6 Detailed Description9	10 Mechanical, Packaging, and Orderable	
6.1 Overview9	Information	. 11



## 3 Pin Configuration and Functions

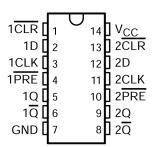


Figure 3-1. D, N, or J Package 14-Pin SOIC, PDIP, or CDIP (Top View)

**Table 3-1. Pin Functions** 

P	IN	TYPE1	DESCRIPTION
NAME	NO.	ITPE	DESCRIPTION
1CLR	1	I	Asynchronous clear for channel 1, active low
1D	2	I	Data for channel 1
1CLK	3	I	Clock for channel 1, rising edge triggered
1PRE	4	I	Asynchronous preset for channel 1, active low
1Q	5	0	Output for channel 1
1Q	6	0	Inverted output for channel 1
GND	7	G	Ground
2Q	8	0	Inverted output for channel 2
2Q	9	0	Output for channel 2
2PRE	10	I	Asynchronous preset for channel 2, active low
2CLK	11	I	Clock for channel 2, rising edge triggered
2D	12	I	Data for channel 2
2CLR	13	I	Asynchronous clear for channel 2, active low
V <sub>CC</sub>	14	Р	Positive supply

1. Signal Types: I = Input, O = Output, I/O = Input or Output.



### 4 Specifications

#### 4.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage range,		-0.5	6	V
I <sub>IK</sub> (2)	Input clamp current	$(V_1 < 0 \text{ or } V_1 > V_{CC})$		±20	mA
I <sub>OK</sub> (2)	Output clamp current	$(V_O < 0 \text{ or } V_O > V_{CC})$		±50	mA
Io	Continuous output current	$(V_O = 0 \text{ to } V_{CC})$		±50	mA
	Continuous current through V <sub>CC</sub> or GND			±100	mA
T <sub>stg</sub>	Storage temperature range		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### 4.2 ESD Ratings

			VALUE	UNIT
V <sub>(ESD)</sub>	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/ JEDEC JS-001 <sup>(1)</sup>	±2000	V

<sup>(1)</sup> AEC Q100-002 indicate that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

#### 4.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)<sup>(1)</sup>

		T <sub>A</sub> = 2	T <sub>A</sub> = 25 °C		-55°C to 125°C		85°C	UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	UNII
V <sub>CC</sub>	Supply voltage	4.5	5.5	4.5	5.5	4.5	5.5	V
V <sub>IH</sub>	High-level input voltage	2		2		2		V
V <sub>IL</sub>	Low-level input voltage		0.8		0.8		0.8	V
VI	Input voltage	0	V <sub>CC</sub>	0	V <sub>CC</sub>	0	V <sub>CC</sub>	V
Vo	Output voltage	0	V <sub>CC</sub>	0	V <sub>CC</sub>	0	V <sub>CC</sub>	V
I <sub>OH</sub>	High-level output current		-24		-24		-24	mA
I <sub>OL</sub>	Low-level output current		24		24		24	mA
Δt/Δν	Input transition rise or fall rate		10		10		10	ns/V

<sup>(1)</sup> All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

#### 4.4 Thermal Information

		CD74	ACT74	
THERMAL METRIC(1)		N (PDIP)	D (SOIC)	UNIT
		14 PINS	14 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	80	119.9	°C/W

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

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<sup>(2)</sup> The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

#### 4.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V <sub>cc</sub>	T <sub>A</sub> = 2	5°C	-55°C to	125°C	-40°C to	85°C	UNIT	
PARAMETER	1231 00	TEST CONDITIONS		MIN	MAX	MIN	MAX	MIN	MAX	ONII	
		I <sub>OH</sub> = -50 μA	4.5 V	4.4		4.4		4.4			
\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	$V_{I} = V_{IH}$ or $V_{IL}$	I <sub>OH</sub> = -24 mA	4.5 V	3.94		3.7		3.8		v	
V <sub>OH</sub>	VI - VIH OI VIL	I <sub>OH</sub> = -50 mA <sup>(1)</sup>	5.5 V			3.85				v	
		I <sub>OH</sub> = -75 mA <sup>(1)</sup>	5.5 V					3.85			
	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 50 μA	4.5 V		0.1		0.1		0.1		
\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \		I <sub>OL</sub> = 24 mA	4.5 V		0.36		0.5		0.44	v	
V <sub>OL</sub>		I <sub>OL</sub> = 50 mA <sup>(1)</sup>	5.5 V				1.65			, v	
		I <sub>OL</sub> = 75 mA <sup>(1)</sup>	5.5 V						1.65		
I <sub>I</sub>	$V_I = V_{CC}$ or GND		5.5 V		±0.1		±1		±1	μA	
I <sub>CC</sub>	$V_I = V_{CC}$ or GND,	I <sub>O</sub> = 0	5.5 V		4		80		40	μA	
ΔI <sub>CC</sub> (2)	V <sub>I</sub> = V <sub>CC</sub> - 2.1 V		4.5 V to 5.5 V		2.4		3		2.8	mA	
C <sub>i</sub>					10		10		10	pF	

<sup>(1)</sup> Test one output at a time, not exceeding 1-second duration. Measurement is made by forcing indicated current and measuring voltage to minimize power dissipation. Test verifies a minimum 50-Ω transmission-line drive capability at 85°C and 75-Ω transmission-line drive capability at 125°C.

Table 4-1. Act Input Load Table

INPUT	UNIT LOAD
Data	0.53
PRE or CLR	0.58
CLK	1

#### 4.6 Timing Requirements

over recommended operating free-air temperature range,  $V_{CC}$  = 5 V  $\pm$  0.5 V (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

	·		-55°C to	125°C	-40°C to 85°C		UNIT
			MIN	MIN MAX MIN MAX		MAX	UNII
f <sub>clock</sub>	Clock frequency			85		97	MHz
A Bulandametica	PRE or CLR low	5		4.4		20	
I <sub>W</sub>	Pulse duration	CLK	5.7		5		ns
	Cotun time	Data	4		3.5		ns
t <sub>su</sub>	Setup time	PRE or CLR inactive					ns
t <sub>h</sub>	Hold time	Data after CLK↑	0		0		ns
t <sub>rec</sub>	Recovery time, before CLKT	CL R↑ or PRE↑	2.7		2.4		ns

### 4.7 Switching Characteristics

over recommended operating free-air temperature range,  $V_{CC}$  = 5 V  $\pm$  0.5 V (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	-55°C to 1	125°C	-40°C to 85°C		UNIT
	PROW (MPOT)	10 (001701)	MIN	MAX	MIN	MAX	ONII
f <sub>max</sub>			85		97		MHz
t <sub>PLH</sub>	CLK	O or $\overline{\Omega}$	2.4	9.5	2.5	8.6	no
t <sub>PHL</sub>	OLK	Q or Q	2.4	9.5	2.5	8.6	ns

<sup>(2)</sup> Additional quiescent supply current per input pin, TTL inputs high, 1 unit load



over recommended operating free-air temperature range,  $V_{CC}$  = 5 V ± 0.5 V (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	-55°C to	125°C	-40°C to	85°C	UNIT
PARAMETER	PROW (NAPOT)	10 (001701)	MIN MA	MAX	MIN	MAX	
t <sub>PLH</sub>	PRE or CLR	Q or $\overline{\mathbb{Q}}$	2.9	11.5	3	10.5	20
t <sub>PHL</sub>	PRE OF CER	Q OI Q	3.1	12.5	3.2	11.4	ns

## 4.8 Operating Characteristics

 $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$ 

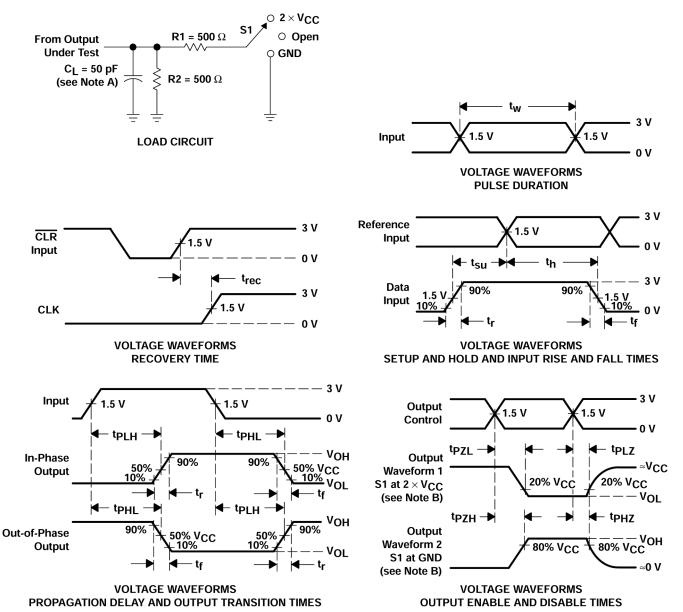
PARAMETER	TYP	UNIT	
C <sub>pd</sub> Power dissipation capacitance	55	pF	

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#### **5 Parameter Measurement Information**



- A. C<sub>L</sub> includes probe and test-fixture capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \Omega$ ,  $t_r = 3$  ns. Phase relationships between waveforms are arbitrary.
- D. For clock inputs,  $f_{\text{max}}$  is measured with the input duty cycle at 50%.
- E. The outputs are measured one at a time with one input transition per measurement.
- F.  $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .
- G.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .
- H. t<sub>PLZ</sub> and t<sub>PHZ</sub> are the same as t<sub>dis</sub>.

Figure 5-1. Load Circuit and Voltage Waveforms

TEST	S1
t <sub>PLH</sub> /t <sub>PHL</sub>	Open



TEST	S1
t <sub>PLZ</sub> /t <sub>PZL</sub>	2 × V <sub>CC</sub>
t <sub>PHZ</sub> /t <sub>PZH</sub>	GND

### **6 Detailed Description**

#### 6.1 Overview

A low level at the preset  $(\overline{PRE})$  or clear  $(\overline{CLR})$  inputs sets or resets the outputs, regardless of the levels of the other inputs. When  $\overline{PRE}$  and  $\overline{CLR}$  are inactive (high), data at the data (D) input meeting the setup time requirements is transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not related directly to the rise time of the clock pulse. Following the hold-time interval, data at the D input can be changed without affecting the levels at the outputs.

#### 6.2 Functional Block Diagram

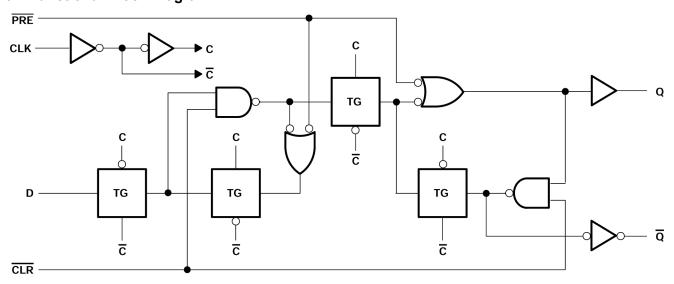


Figure 6-1. Logic Diagram, Each Flip-flop (Positive Logic)

#### **6.3 Device Functional Modes**

Function Table (Each Flip-Flop)

	INPUTS							
PRE	CLR	CLK	D	Q	Q			
L	Н	Х	Χ	Н	L			
Н	L	Х	Χ	L	Н			
L	L	Х	Χ	H <sup>(1)</sup>	H <sup>(1)</sup>			
Н	Н	1	Н	Н	L			
Н	Н	1	L	L	Н			
Н	Н	L	Χ	$Q_0$	$\overline{Q}_0$			

(1) This configuration is nonstable; that is, it does not persist when PRE or CLR returns to its inactive (high) level.

### 7 Application and Implementation

#### Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

#### 7.1 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the Section 4.3. Each  $V_{CC}$  terminal should have a bypass capacitor to prevent power disturbance. A 0.1- $\mu$ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1- $\mu$ F and 1- $\mu$ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

#### 7.2 Layout

#### 7.2.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or  $V_{CC}$ , whichever makes more sense for the logic function or is more convenient.

#### 7.2.2 Layout Example

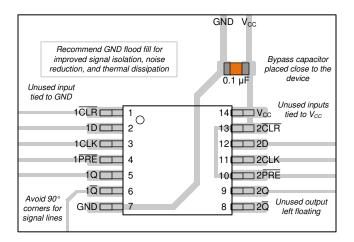


Figure 7-1. Example layout for the CD74ACT74

### 8 Device and Documentation Support

#### 8.1 Documentation Support (Analog)

#### 8.1.1 Related Links

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

PARTS	PRODUCT FOLDER	SAMPLE & BUY	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY
CD54ACT74	Click here	Click here	Click here	Click here	Click here
CD74ACT74	Click here	Click here	Click here	Click here	Click here

### 8.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

#### 8.3 Support Resources

TI E2E<sup>™</sup> support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

#### 8.4 Trademarks

TI E2E<sup>™</sup> is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

#### 8.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 8.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

#### 9 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

#### Changes from Revision \* (December 2002) to Revision A (July 2024)

Page

- Added Device Information table, Pin Functions table, ESD Ratings table, Thermal Information table, Device
  Functional Modes, Application and Implementation section, Device and Documentation Support section, and
  Mechanical, Packaging, and Orderable Information section
- Updated RθJA values: D = 86 to 119.9, all values in °C/W......4

### 10 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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#### PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
CD54ACT74F3A	ACTIVE	CDIP	J	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	CD54ACT74F3A	Samples
CD74ACT74E	ACTIVE	PDIP	N	14	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74ACT74E	Samples
CD74ACT74M	OBSOLETE	SOIC	D	14		TBD	Call TI	Call TI	-55 to 125	ACT74M	
CD74ACT74M96	ACTIVE	SOIC	D	14	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	ACT74M	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and

### **PACKAGE OPTION ADDENDUM**

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continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### OTHER QUALIFIED VERSIONS OF CD54ACT74, CD74ACT74:

Catalog : CD74ACT74

Automotive: CD74ACT74-Q1, CD74ACT74-Q1

Military: CD54ACT74

NOTE: Qualified Version Definitions:

• Catalog - TI's standard catalog product

Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

• Military - QML certified for Military and Defense Applications

## **PACKAGE MATERIALS INFORMATION**

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#### TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74ACT74M96	SOIC	D	14	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1

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#### \*All dimensions are nominal

	Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ı	CD74ACT74M96	SOIC	D	14	2500	356.0	356.0	35.0

## **PACKAGE MATERIALS INFORMATION**

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#### **TUBE**



#### \*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
CD74ACT74E	N	PDIP	14	25	506	13.97	11230	4.32
CD74ACT74E	N	PDIP	14	25	506	13.97	11230	4.32

CERAMIC DUAL IN LINE PACKAGE



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4040083-5/G





CERAMIC DUAL IN LINE PACKAGE



- 1. All controlling linear dimensions are in inches. Dimensions in brackets are in millimeters. Any dimension in brackets or parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This package is hermitically sealed with a ceramic lid using glass frit.
- His package is remitted by sealed with a ceramic its using glass mit.
   Index point is provided on cap for terminal identification only and on press ceramic glass frit seal only.
   Falls within MIL-STD-1835 and GDIP1-T14.



CERAMIC DUAL IN LINE PACKAGE



## D (R-PDSO-G14)

### PLASTIC SMALL OUTLINE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AB.



# D (R-PDSO-G14)

## PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



## N (R-PDIP-T\*\*)

## PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



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